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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	1452
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	175
Number of Gates	24000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	208-BFQFP
Supplier Device Package	208-PQFP (28x28)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a54sx16-1pq208

Chip Architecture

The SX family chip architecture provides a unique approach to module organization and chip routing that delivers the best register/logic mix for a wide variety of new and emerging applications.

Module Organization

Actel has arranged all C-cell and R-cell logic modules into horizontal banks called *clusters*. There are two types of *clusters*: Type 1 contains two C-cells and one R-cell, while Type 2 contains one C-cell and two R-cells.

To increase design efficiency and device performance, Actel has further organized these modules into *SuperClusters* (Figure 1-4). SuperCluster 1 is a two-wide grouping of Type 1 clusters. SuperCluster 2 is a two-wide group containing one Type 1 cluster and one Type 2 cluster. SX devices feature more SuperCluster 1 modules than SuperCluster 2 modules because designers typically require significantly more combinatorial logic than flip-flops.

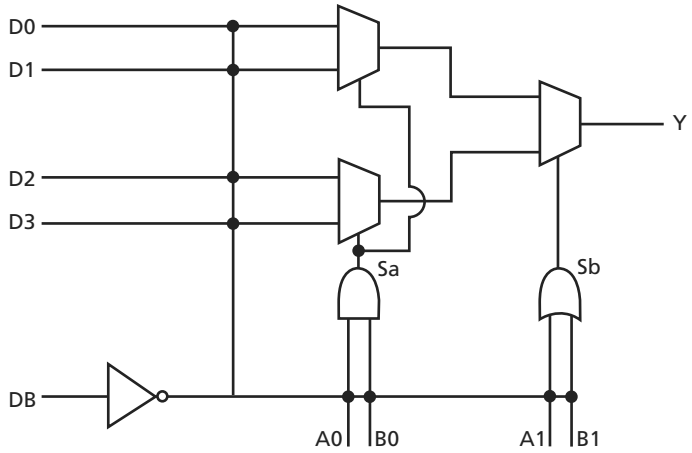


Figure 1-3 • **C-Cell**

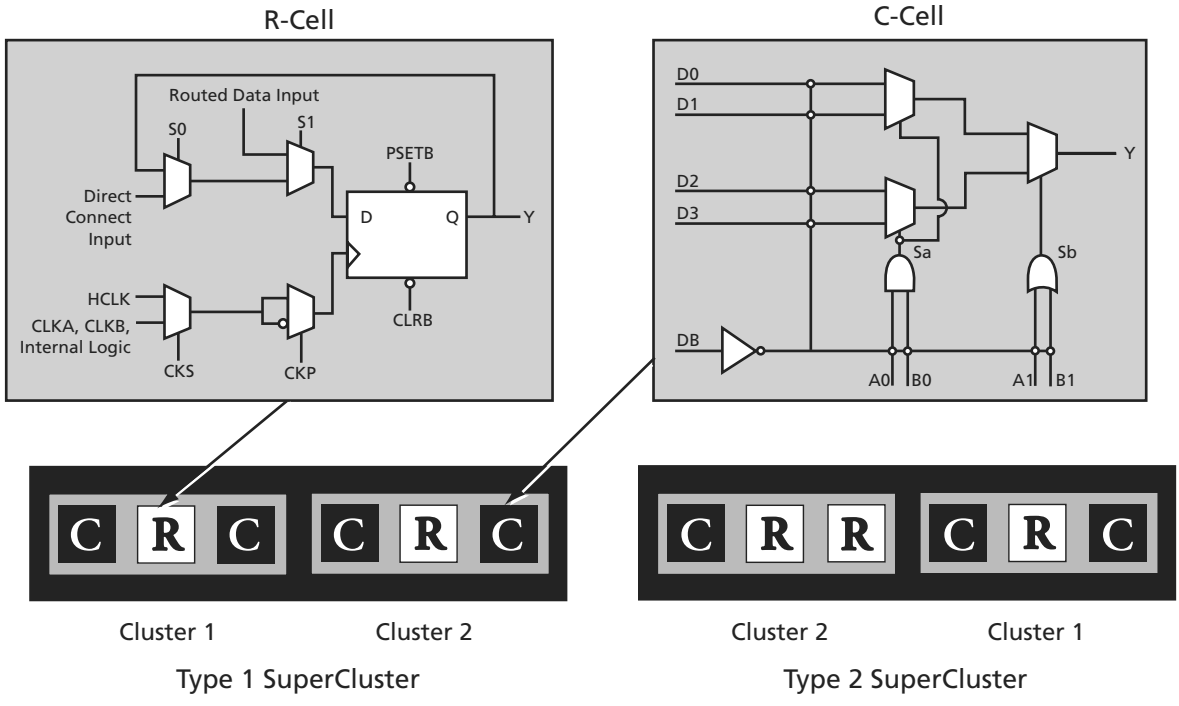


Figure 1-4 • **Cluster Organization**

Boundary Scan Testing (BST)

All SX devices are IEEE 1149.1 compliant. SX devices offer superior diagnostic and testing capabilities by providing Boundary Scan Testing (BST) and probing capabilities. These functions are controlled through the special test pins in conjunction with the program fuse. The functionality of each pin is described in Table 1-2. In the dedicated test mode, TCK, TDI, and TDO are dedicated pins and cannot be used as regular I/Os. In flexible mode, TMS should be set HIGH through a pull-up resistor of 10 kΩ. TMS can be pulled LOW to initiate the test sequence.

The program fuse determines whether the device is in dedicated or flexible mode. The default (fuse not blown) is flexible mode.

Table 1-2 • **Boundary Scan Pin Functionality**

Program Fuse Blown (Dedicated Test Mode)	**Program Fuse Not Blown (Flexible Mode)**
TCK, TDI, TDO are dedicated BST pins.	TCK, TDI, TDO are flexible and may be used as I/Os.
No need for pull-up resistor for TMS	Use a pull-up resistor of 10 kΩ on TMS.

Dedicated Test Mode

In Dedicated mode, all JTAG pins are reserved for BST; designers cannot use them as regular I/Os. An internal pull-up resistor is automatically enabled on both TMS and TDI pins, and the TMS pin will function as defined in the IEEE 1149.1 (JTAG) specification.

To select Dedicated mode, users need to reserve the JTAG pins in Actel's Designer software by checking the "Reserve JTAG" box in "Device Selection Wizard" (Figure 1-7). JTAG pins comply with LVTTL/TTL I/O specification regardless of whether they are used as a user I/O or a JTAG I/O. Refer to the Table 1-5 on page 1-8 for detailed specifications.

Figure 1-7 • **Device Selection Wizard**

Development Tool Support

The SX family of FPGAs is fully supported by both the Actel Libero® Integrated Design Environment (IDE) and Designer FPGA Development software. Actel Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes Synplify® for Actel from Synplicity®, ViewDraw® for Actel from Mentor Graphics®, Model*Sim*® HDL Simulator from Mentor Graphics, WaveFormer Lite™ from SynaptiCAD™, and Designer software from Actel. Refer to the Libero IDE flow diagram (located on the Actel website) for more information.

Actel Designer software is a place-and-route tool and provides a comprehensive suite of backend support tools for FPGA development. The Designer software includes timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor. With the Designer software, a user can select and lock package pins while only minimally impacting the results of place-and-route. Additionally, the back-annotation flow is compatible with all the major simulators, and the simulation results can be cross-probed with Silicon Explorer II, Actel integrated verification and logic analysis tool. Another tool included in the Designer software is the SmartGen core generator, which easily creates popular and commonly used logic functions for implementation into your schematic or HDL design. Actel Designer software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synplicity, Synopsys®, and Cadence® Design Systems. The Designer software is available for both the Windows® and UNIX® operating systems.

Probe Circuit Control Pins

The Silicon Explorer II tool uses the boundary scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the PRA/PRB pins for observation. Figure 1-8 on page 1-7 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

Design Considerations

The TDI, TCK, TDO, PRA, and PRB pins should not be used as input or bidirectional ports. Because these pins are active during probing, critical signals input through these pins are not available while probing. In addition, the Security Fuse should not be programmed because doing so disables the Probe Circuitry.

Table 1-4 • **Recommended Operating Conditions**

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to + 70	–40 to + 85	–55 to +125	°C
3.3 V Power Supply Tolerance	±10	±10	±10	%V_{CC}
5.0 V Power Supply Tolerance	±5	±10	±10	%V_{CC}

Note: **Ambient temperature (T_A) is used for commercial and industrial; case temperature (T_C) is used for military.*

Table 1-5 • **Electrical Specifications**

		Commercial		Industrial		
Symbol	**Parameter**	**Min.**	**Max.**	**Min.**	**Max.**	**Units**
V_{OH}	(I_{OH} = –20 µA) (CMOS) (I_{OH} = –8 mA) (TTL) (I_{OH} = –6 mA) (TTL)	(V_{CCI} – 0.1) 2.4	V_{CCI} V_{CCI}	(V_{CCI} – 0.1) 2.4	V_{CCI} V_{CCI}	V
V_{OL}	(I_{OL}= 20 µA) (CMOS) (I_{OL} = 12 mA) (TTL) (I_{OL} = 8 mA) (TTL)		0.10 0.50		 0.50	V
V_{IL}			0.8		0.8	V
V_{IH}		2.0		2.0		V
t_R, t_F	Input Transition Time t_R, t_F		50		50	ns
C_{IO}	C_{IO} I/O Capacitance		10		10	pF
I_{CC}	Standby Current, I_{CC}		4.0		4.0	mA
$I_{CC(D)}$	$I_{CC(D)}$ $I_{Dynamic}$ V_{CC} Supply Current	See "Evaluating Power in SX Devices" on page 1-16.				

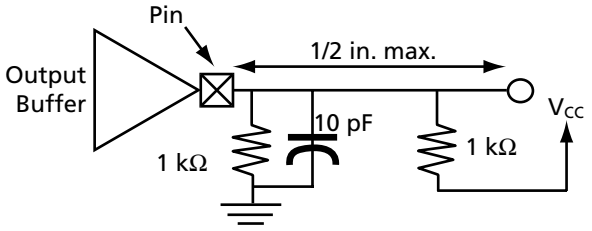
A54SX16P AC Specifications for (PCI Operation)

Table 1-7 • **A54SX16P AC Specifications for (PCI Operation)**

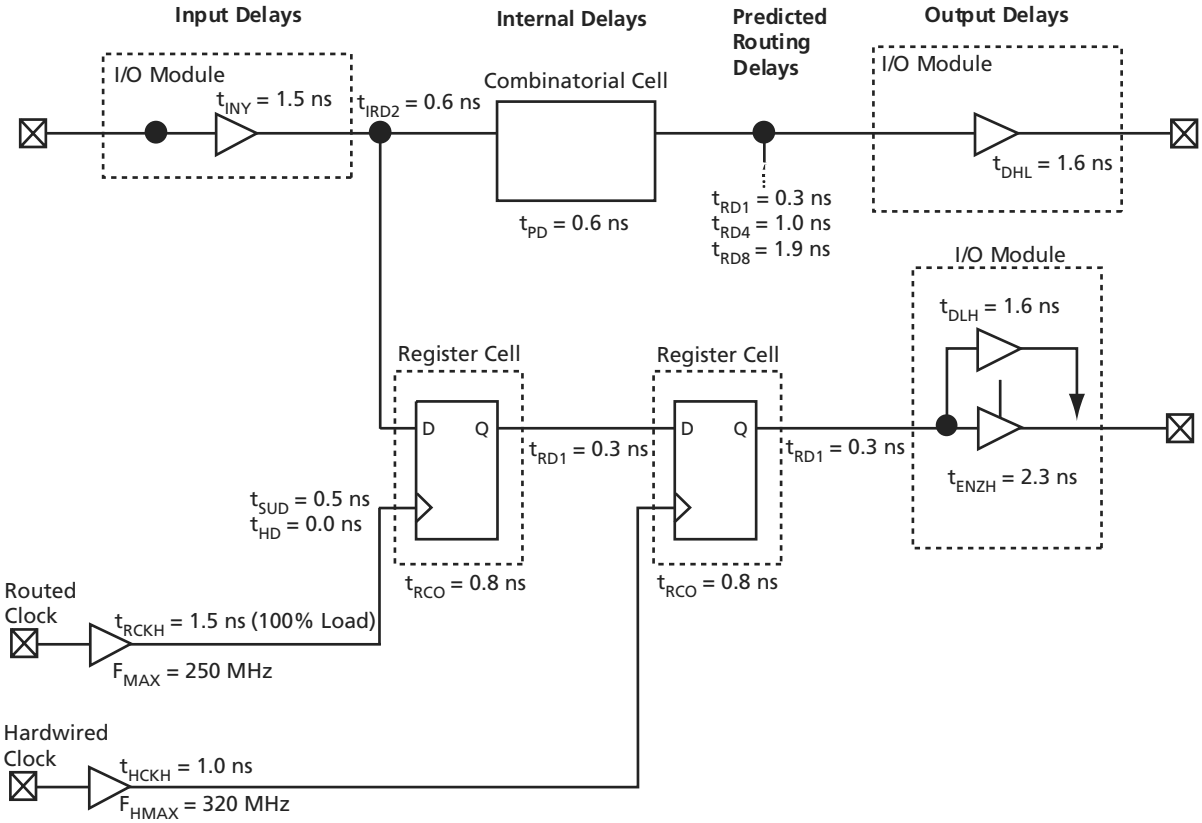
Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \le 1.4$[1]	–44		mA
		$1.4 \le V_{OUT} < 2.4$[1, 2]	$–44 + (V_{OUT} – 1.4)/0.024$		mA
		$3.1 < V_{OUT} < V_{CC}$[1, 3]		EQ 1-1 on page 1-11	
	(Test Point)	$V_{OUT} = 3.1$[3]		–142	mA
$I_{OL(AC)}$	Switching Current High	$V_{OUT} \ge 2.2$[1]	95		mA
		$2.2 > V_{OUT} > 0.55$[1]	$V_{OUT}/0.023$		
		$0.71 > V_{OUT} > 0$[1, 3]		EQ 1-2 on page 1-11	mA
	(Test Point)	$V_{OUT} = 0.71$[3]		206	mA
I_{CL}	Low Clamp Current	$–5 < V_{IN} \le –1$	$–25 + (V_{IN} + 1)/0.015$		mA
$slew_R$	Output Rise Slew Rate	0.4 V to 2.4 V load[4]	1	5	V/ns
$slew_F$	Output Fall Slew Rate	2.4 V to 0.4 V load[4]	1	5	V/ns

Notes:

1. *Refer to the V/I curves in Figure 1-9 on page 1-11. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half-size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.*
2. *Note that this segment of the minimum current curve is drawn from the AC drive point directly to the DC drive point rather than toward the voltage rail (as is done in the pull-down curve). This difference is intended to allow for an optional N-channel pull-up.*
3. *Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (A and B) are provided with the respective diagrams in Figure 1-9 on page 1-11. The equation defined maxima should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.*
4. *This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per revision 2.0 of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is now required (the maximum is no longer simply a guideline). Since adherence to the maximum slew rate was not required prior to revision 2.1 of the specification, there may be components in the market for some time that have faster edge rates; therefore, motherboard designers must bear in mind that rise and fall times faster than this specification could occur, and should ensure that signal integrity modeling accounts for this. Rise slew rate does not apply to open drain outputs.*



SX Timing Model



Note: *Values shown for A54SX08-3, worst-case commercial conditions.*

Figure 1-12 • **SX Timing Model**

Hardwired Clock

External Setup = $t_{INY} + t_{IRD1} + t_{SUD} - t_{HCKH}$
= 1.5 + 0.3 + 0.5 – 1.0 = 1.3 ns

EQ 1-15

Clock-to-Out (Pin-to-Pin)

= $t_{HCKH} + t_{RCO} + t_{RD1} + t_{DHL}$
= 1.0 + 0.8 + 0.3 + 1.6 = 3.7 ns

EQ 1-16

Routed Clock

External Setup = $t_{INY} + t_{IRD1} + t_{SUD} - t_{RCKH}$
= 1.5 + 0.3 + 0.5 – 1.5 = 0.8 ns

EQ 1-17

Clock-to-Out (Pin-to-Pin)

= $t_{RCKH} + t_{RCO} + t_{RD1} + t_{DHL}$
= 1.52+ 0.8 + 0.3 + 1.6 = 4.2 ns

EQ 1-18

Table 1-19 • **A54SX16P Timing Characteristics (Continued)**
(Worst-Case Commercial Conditions, V_{CCR} = 4.75 V, V_{CCA},V_{CCI} = 3.0 V, T_J = 70°C)

Parameter	Description	'–3' Speed		'–2' Speed		'–1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Network										
t_{HCKH}	Input LOW to HIGH (pad to R-Cell input)		1.2		1.4		1.5		1.8	ns
t_{HCKL}	Input HIGH to LOW (pad to R-Cell input)		1.2		1.4		1.6		1.9	ns
t_{HPWH}	Minimum Pulse Width HIGH	1.4		1.6		1.8		2.1		ns
t_{HPWL}	Minimum Pulse Width LOW	1.4		1.6		1.8		2.1		ns
t_{HCKSW}	Maximum Skew		0.2		0.2		0.3		0.3	ns
t_{HP}	Minimum Period	2.7		3.1		3.6		4.2		ns
f_{HMAX}	Maximum Frequency		350		320		280		240	MHz
Routed Array Clock Networks										
t_{RCKH}	Input LOW to HIGH (light load) (pad to R-Cell input)		1.6		1.8		2.1		2.5	ns
t_{RCKL}	Input HIGH to LOW (Light Load) (pad to R-Cell input)		1.8		2.0		2.3		2.7	ns
t_{RCKH}	Input LOW to HIGH (50% load) (pad to R-Cell input)		1.8		2.1		2.5		2.8	ns
t_{RCKL}	Input HIGH to LOW (50% load) (pad to R-Cell input)		2.0		2.2		2.5		3.0	ns
t_{RCKH}	Input LOW to HIGH (100% load) (pad to R-Cell input)		1.8		2.1		2.4		2.8	ns
t_{RCKL}	Input HIGH to LOW (100% load) (pad to R-Cell input)		2.0		2.2		2.5		3.0	ns
t_{RPWH}	Min. Pulse Width HIGH	2.1		2.4		2.7		3.2		ns
t_{RPWL}	Min. Pulse Width LOW	2.1		2.4		2.7		3.2		ns
t_{RCKSW}	Maximum Skew (light load)		0.5		0.5		0.5		0.7	ns
t_{RCKSW}	Maximum Skew (50% load)		0.5		0.6		0.7		0.8	ns
t_{RCKSW}	Maximum Skew (100% load)		0.5		0.6		0.7		0.8	ns
TTL Output Module Timing										
t_{DLH}	Data-to-Pad LOW to HIGH		2.4		2.8		3.1		3.7	ns
t_{DHL}	Data-to-Pad HIGH to LOW		2.3		2.9		3.2		3.8	ns
t_{ENZL}	Enable-to-Pad, Z to L		3.0		3.4		3.9		4.6	ns
t_{ENZH}	Enable-to-Pad, Z to H		3.3		3.8		4.3		5.0	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.3		2.7		3.0		3.5	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.8		3.2		3.7		4.3	ns

Note:

1. *For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn}, t_{RCO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*
3. *Delays based on 10 pF loading.*

Table 1-19 • **A54SX16P Timing Characteristics (Continued)**
(Worst-Case Commercial Conditions, V_{CCR} = 4.75 V, V_{CCA},V_{CCI} = 3.0 V, T_J = 70°C)

Parameter	Description	'–3' Speed		'–2' Speed		'–1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL/PCI Output Module Timing										
t_{DLH}	Data-to-Pad LOW to HIGH		1.5		1.7		2.0		2.3	ns
t_{DHL}	Data-to-Pad HIGH to LOW		1.9		2.2		2.4		2.9	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.3		2.6		3.0		3.5	ns
t_{ENZH}	Enable-to-Pad, Z to H		1.5		1.7		1.9		2.3	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.7		3.1		3.5		4.1	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.9		3.3		3.7		4.4	ns
PCI Output Module Timing[3]										
t_{DLH}	Data-to-Pad LOW to HIGH		1.8		2.0		2.3		2.7	ns
t_{DHL}	Data-to-Pad HIGH to LOW		1.7		2.0		2.2		2.6	ns
t_{ENZL}	Enable-to-Pad, Z to L		0.8		1.0		1.1		1.3	ns
t_{ENZH}	Enable-to-Pad, Z to H		1.2		1.2		1.5		1.8	ns
t_{ENLZ}	Enable-to-Pad, L to Z		1.0		1.1		1.3		1.5	ns
t_{ENHZ}	Enable-to-Pad, H to Z		1.1		1.3		1.5		1.7	ns
TTL Output Module Timing										
t_{DLH}	Data-to-Pad LOW to HIGH		2.1		2.5		2.8		3.3	ns
t_{DHL}	Data-to-Pad HIGH to LOW		2.0		2.3		2.6		3.1	ns
t_{ENZL}	Enable-to-Pad, Z to L		2.5		2.9		3.2		3.8	ns
t_{ENZH}	Enable-to-Pad, Z to H		3.0		3.5		3.9		4.6	ns
t_{ENLZ}	Enable-to-Pad, L to Z		2.3		2.7		3.1		3.6	ns
t_{ENHZ}	Enable-to-Pad, H to Z		2.9		3.3		3.7		4.4	ns

Note:

1. *For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn}, t_{RCO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*
3. *Delays based on 10 pF loading.*

A54SX32 Timing Characteristics

Table 1-20 • **A54SX32 Timing Characteristics (Worst-Case Commercial Conditions, V_{CCR}= 4.75 V, V_{CCA},V_{CCI} = 3.0 V, T_J = 70°C)**

Parameter	Description	'–3' Speed		'–2' Speed		'–1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays[1]										
t_{PD}	Internal Array Module		0.6		0.7		0.8		0.9	ns
Predicted Routing Delays[2]										
t_{DC}	FO = 1 Routing Delay, Direct Connect		0.1		0.1		0.1		0.1	ns
t_{FC}	FO = 1 Routing Delay, Fast Connect		0.3		0.4		0.4		0.5	ns
t_{RD1}	FO = 1 Routing Delay		0.3		0.4		0.4		0.5	ns
t_{RD2}	FO = 2 Routing Delay		0.7		0.8		0.9		1.0	ns
t_{RD3}	FO = 3 Routing Delay		1.0		1.2		1.4		1.6	ns
t_{RD4}	FO = 4 Routing Delay		1.4		1.6		1.8		2.1	ns
t_{RD8}	FO = 8 Routing Delay		2.7		3.1		3.5		4.1	ns
t_{RD12}	FO = 12 Routing Delay		4.0		4.7		5.3		6.2	ns
R-Cell Timing										
t_{RCO}	Sequential Clock-to-Q		0.8		1.1		1.3		1.4	ns
t_{CLR}	Asynchronous Clear-to-Q		0.5		0.6		0.7		0.8	ns
t_{PRESET}	Asynchronous Preset-to-Q		0.7		0.8		0.9		1.0	ns
t_{SUD}	Flip-Flop Data Input Set-Up	0.5		0.6		0.7		0.8		ns
t_{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t_{WASYN}	Asynchronous Pulse Width	1.4		1.6		1.8		2.1		ns
Input Module Propagation Delays										
t_{INYH}	Input Data Pad-to-Y HIGH		1.5		1.7		1.9		2.2	ns
t_{INYL}	Input Data Pad-to-Y LOW		1.5		1.7		1.9		2.2	ns
Predicted Input Routing Delays[2]										
t_{IRD1}	FO = 1 Routing Delay		0.3		0.4		0.4		0.5	ns
t_{IRD2}	FO = 2 Routing Delay		0.7		0.8		0.9		1.0	ns
t_{IRD3}	FO = 3 Routing Delay		1.0		1.2		1.4		1.6	ns
t_{IRD4}	FO = 4 Routing Delay		1.4		1.6		1.8		2.1	ns
t_{IRD8}	FO = 8 Routing Delay		2.7		3.1		3.5		4.1	ns
t_{IRD12}	FO = 12 Routing Delay		4.0		4.7		5.3		6.2	ns

Note:

1. *For dual-module macros, use t_{PD} + t_{RD1} + t_{PDn}, t_{RCO} + t_{RD1} + t_{PDn}, or t_{PD1} + t_{RD1} + t_{SUD}, whichever is appropriate.*
2. *Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.*
3. *Delays based on 35 pF loading, except t_{ENZL} and t_{ENZH}. For t_{ENZL} and t_{ENZH} the loading is 5 pF.*

Pin Description

CLKA/B Clock A and B

These pins are 3.3 V / 5.0 V PCI/TTL clock inputs for clock distribution networks. The clock input is buffered prior to clocking the R-cells. If not used, this pin must be set LOW or HIGH on the board. It must not be left floating. (For A54SX72A, these clocks can be configured as bidirectional.)

GND Ground

LOW supply voltage.

HCLK Dedicated (hardwired) Array Clock

This pin is the 3.3 V / 5.0 V PCI/TTL clock input for sequential modules. This input is directly wired to each R-cell and offers clock speeds independent of the number of R-cells being driven. If not used, this pin must be set LOW or HIGH on the board. It must not be left floating.

I/O Input/Output

The I/O pin functions as an input, output, tristate, or bidirectional buffer. Based on certain configurations, input and output levels are compatible with standard TTL, LVTTL, 3.3 V PCI or 5.0 V PCI specifications. Unused I/O pins are automatically tristated by the Designer Series software.

NC No Connection

This pin is not connected to circuitry within the device.

PRA, I/O Probe A

The Probe A pin is used to output data from any user-defined design node within the device. This independent diagnostic pin can be used in conjunction with the Probe B pin to allow real-time diagnostic output of any signal path within the device. The Probe A pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality.

PRB, I/O Probe B

The Probe B pin is used to output data from any node within the device. This diagnostic pin can be used in conjunction with the Probe A pin to allow real-time diagnostic output of any signal path within the device. The Probe B pin can be used as a user-defined I/O when verification has been completed. The pin's probe capabilities can be permanently disabled to protect programmed design confidentiality.

TCK Test Clock

Test clock input for diagnostic probe and device programming. In flexible mode, TCK becomes active when the TMS pin is set LOW (refer to Table 1-2 on page 1-6). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDI Test Data Input

Serial input for boundary scan testing and diagnostic probe. In flexible mode, TDI is active when the TMS pin is set LOW (refer to Table 1-2 on page 1-6). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TDO Test Data Output

Serial output for boundary scan testing. In flexible mode, TDO is active when the TMS pin is set LOW (refer to Table 1-2 on page 1-6). This pin functions as an I/O when the boundary scan state machine reaches the "logic reset" state.

TMS Test Mode Select

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO). In flexible mode when the TMS pin is set LOW, the TCK, TDI, and TDO pins are boundary scan pins (refer to Table 1-2 on page 1-6). Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the "logic reset" state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The "logic reset" state is reached 5 TCK cycles after the TMS pin is set HIGH. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications.

V_{CCI} Supply Voltage

Supply voltage for I/Os. See Table 1-1 on page 1-5.

V_{CCA} Supply Voltage

Supply voltage for Array. See Table 1-1 on page 1-5.

V_{CCR} Supply Voltage

Supply voltage for input tolerance (required for internal biasing). See Table 1-1 on page 1-5.

144-Pin TQFP

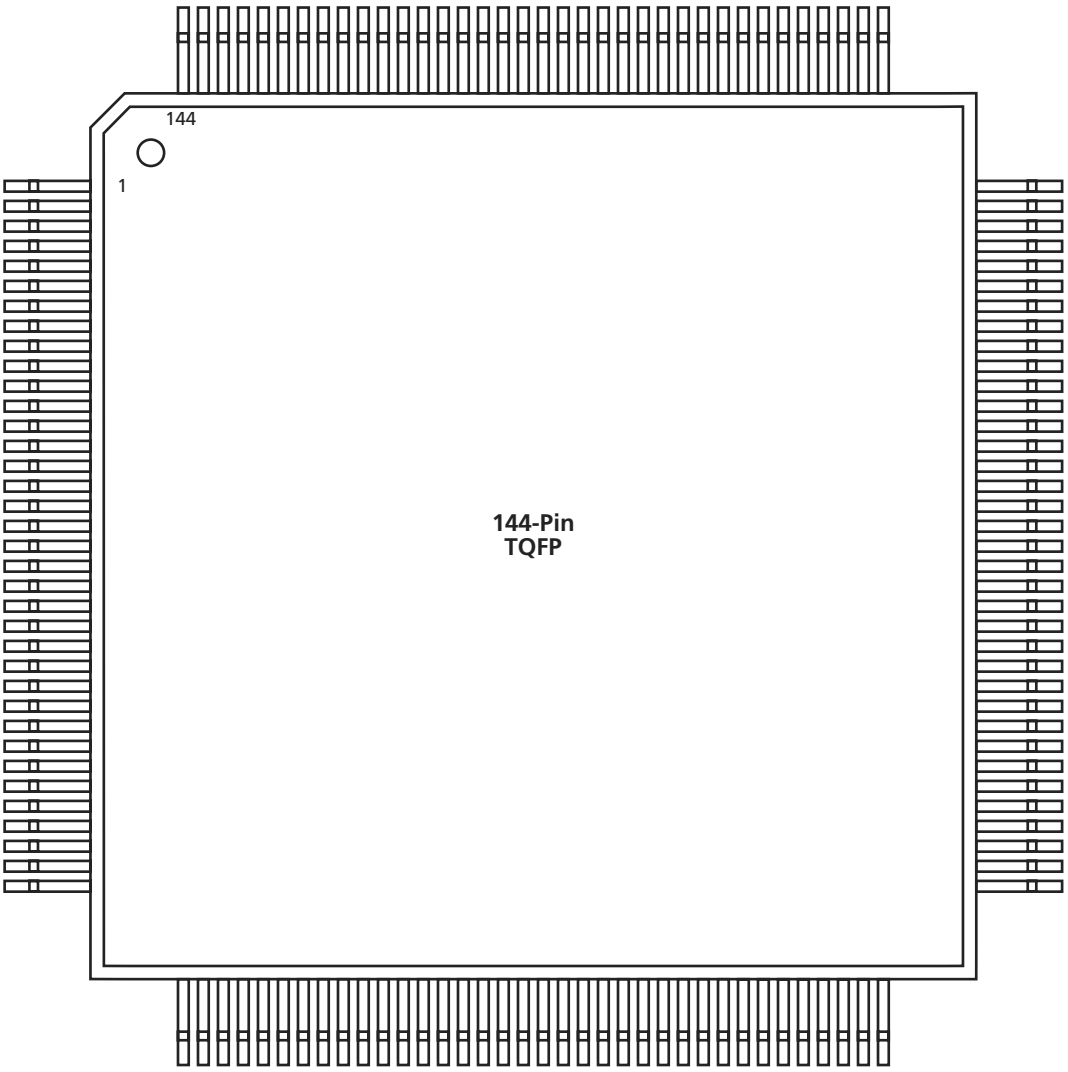


Figure 2-3 • **144-Pin TQFP (Top View)**

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at http://www.actel.com/products/rescenter/package/index.html.

144-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16P Function	A54SX32 Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	TMS	TMS	TMS
10	V_{CCI}	V_{CCI}	V_{CCI}
11	GND	GND	GND
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	V_{CCR}	V_{CCR}	V_{CCR}
20	V_{CCA}	V_{CCA}	V_{CCA}
21	I/O	I/O	I/O
22	I/O	I/O	I/O
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	GND	GND	GND
29	V_{CCI}	V_{CCI}	V_{CCI}
30	V_{CCA}	V_{CCA}	V_{CCA}
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	GND	GND	GND

144-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16P Function	A54SX32 Function
37	I/O	I/O	I/O
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	V_{CCI}	V_{CCI}	V_{CCI}
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	I/O	I/O	I/O
53	I/O	I/O	I/O
54	PRB, I/O	PRB, I/O	PRB, I/O
55	I/O	I/O	I/O
56	V_{CCA}	V_{CCA}	V_{CCA}
57	GND	GND	GND
58	V_{CCR}	V_{CCR}	V_{CCR}
59	I/O	I/O	I/O
60	HCLK	HCLK	HCLK
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	I/O	I/O	I/O
68	V_{CCI}	V_{CCI}	V_{CCI}
69	I/O	I/O	I/O
70	I/O	I/O	I/O
71	TDO, I/O	TDO, I/O	TDO, I/O
72	I/O	I/O	I/O

176-Pin TQFP

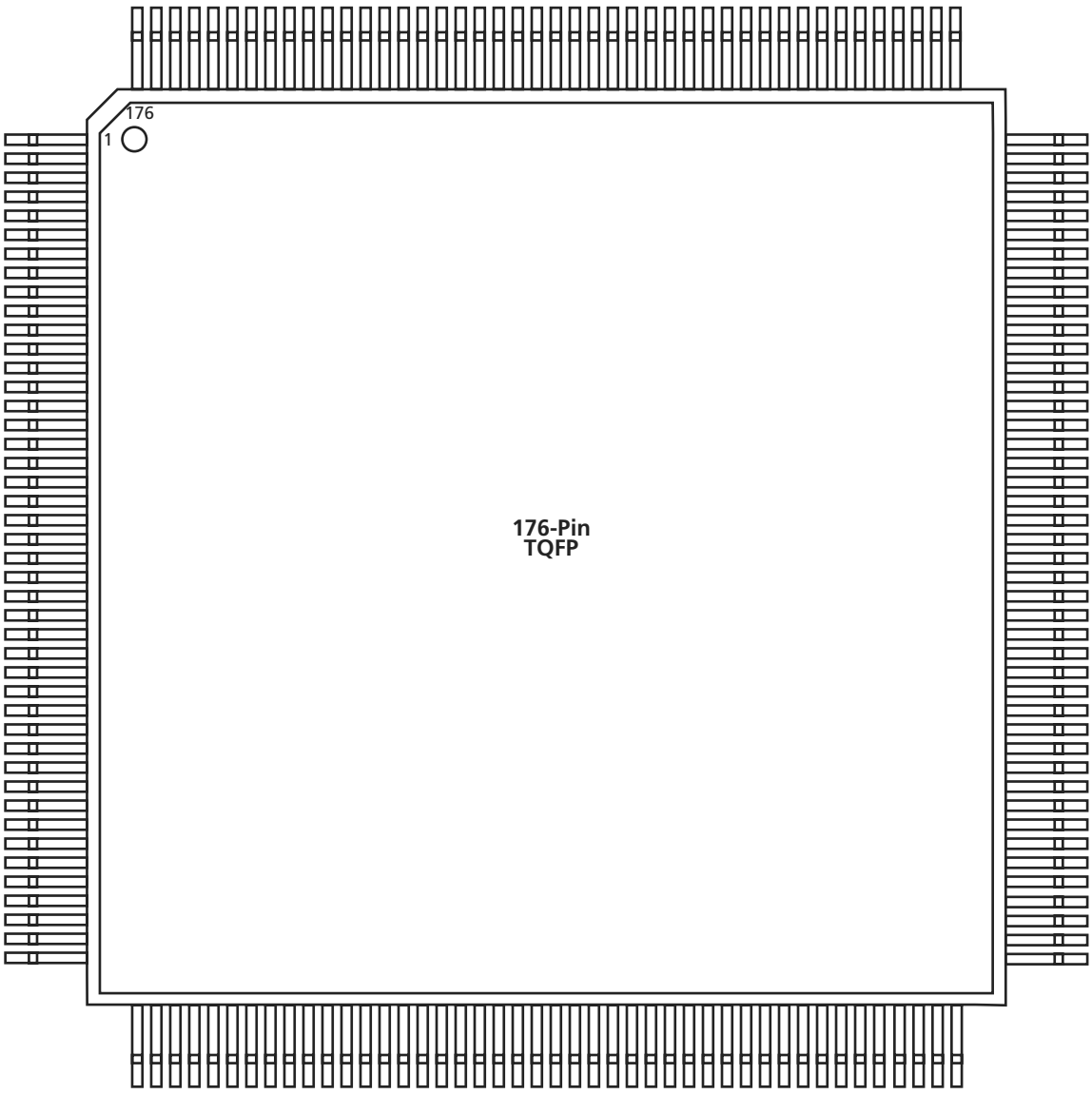


Figure 2-4 • **176-Pin TQFP (Top View)**

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at http://www.actel.com/products/rescenter/package/index.html.

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	NC	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	I/O	I/O	I/O
10	TMS	TMS	TMS
11	V_{CCI}	V_{CCI}	V_{CCI}
12	NC	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	I/O	I/O	I/O
21	GND	GND	GND
22	V_{CCA}	V_{CCA}	V_{CCA}
23	GND	GND	GND
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	I/O	I/O	I/O
29	I/O	I/O	I/O
30	I/O	I/O	I/O
31	I/O	I/O	I/O
32	V_{CCI}	V_{CCI}	V_{CCI}
33	V_{CCA}	V_{CCA}	V_{CCA}
34	I/O	I/O	I/O

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
35	I/O	I/O	I/O
36	I/O	I/O	I/O
37	I/O	I/O	I/O
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	NC	I/O	I/O
41	I/O	I/O	I/O
42	NC	I/O	I/O
43	I/O	I/O	I/O
44	GND	GND	GND
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	V_{CCI}	V_{CCI}	V_{CCI}
53	I/O	I/O	I/O
54	NC	I/O	I/O
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	NC	I/O	I/O
58	I/O	I/O	I/O
59	I/O	I/O	I/O
60	I/O	I/O	I/O
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	PRB, I/O	PRB, I/O	PRB, I/O
65	GND	GND	GND
66	V_{CCA}	V_{CCA}	V_{CCA}
67	V_{CCR}	V_{CCR}	V_{CCR}
68	I/O	I/O	I/O

100-Pin VQFP

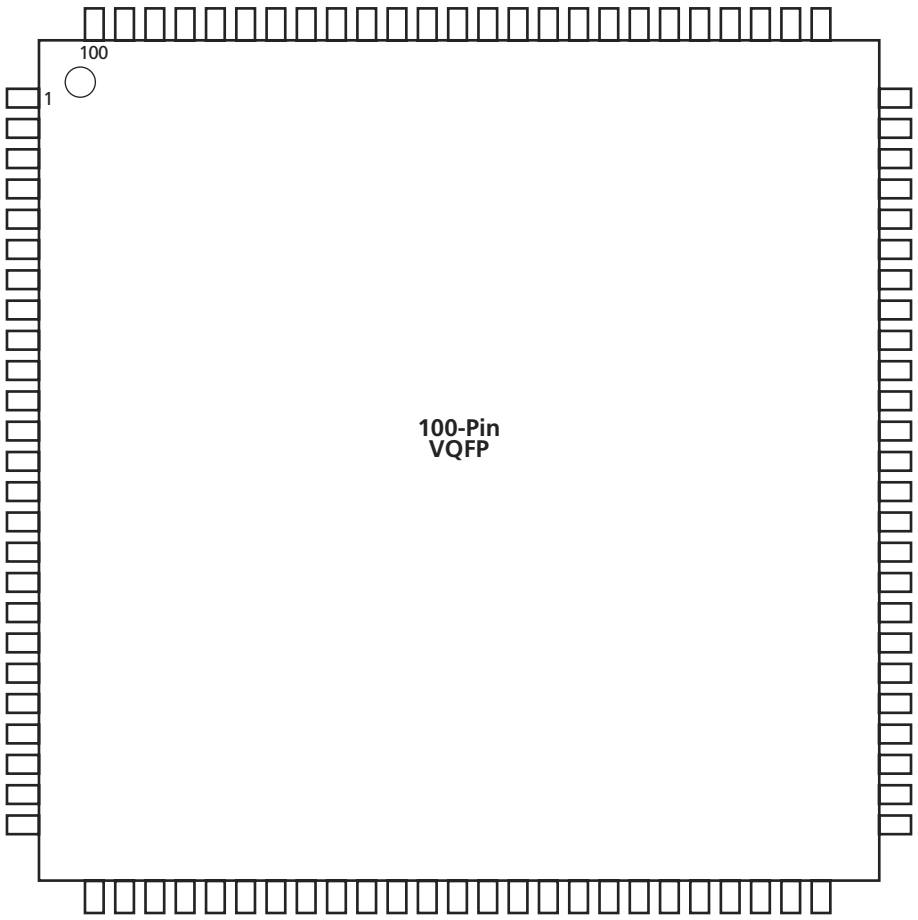


Figure 2-5 • **100-Pin VQFP (Top View)**

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at http://www.actel.com/products/rescenter/package/index.html.

313-Pin PBGA

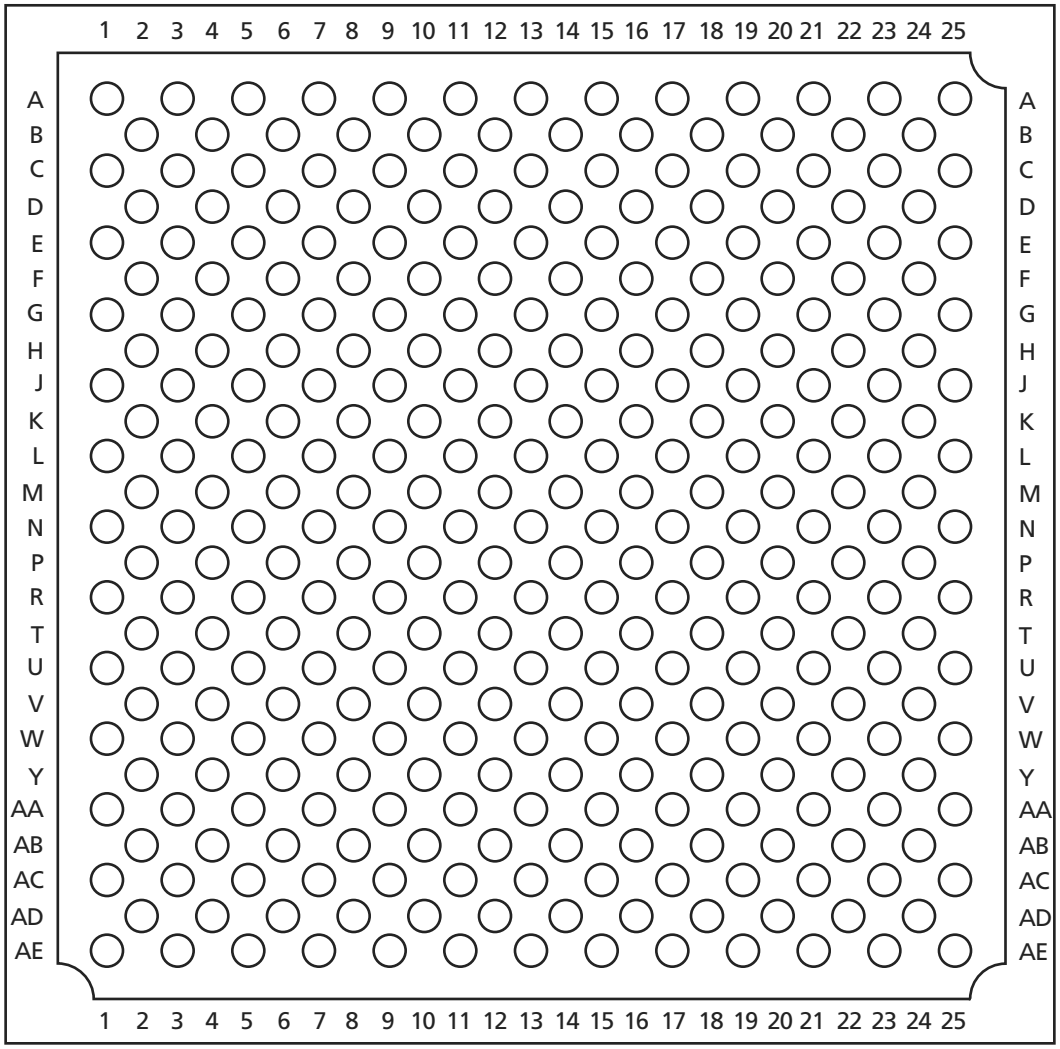


Figure 2-6 • **313-Pin PBGA (Top View)**

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at http://www.actel.com/products/rescenter/package/index.html.

313-Pin PBGA	
Pin Number	**A54SX32 Function**
H20	I/O
H22	V_{CCI}
H24	I/O
J1	I/O
J3	I/O
J5	I/O
J7	NC
J9	I/O
J11	I/O
J13	CLKA
J15	I/O
J17	I/O
J19	I/O
J21	GND
J23	I/O
J25	I/O
K2	I/O
K4	I/O
K6	I/O
K8	V_{CCI}
K10	I/O
K12	I/O
K14	I/O
K16	I/O
K18	I/O
K20	V_{CCA}
K22	I/O
K24	I/O
L1	I/O
L3	I/O
L5	I/O
L7	I/O
L9	I/O
L11	I/O
L13	GND
L15	I/O
L17	I/O
L19	I/O
L21	I/O
L23	I/O

313-Pin PBGA	
Pin Number	**A54SX32 Function**
L25	I/O
M2	I/O
M4	I/O
M6	I/O
M8	I/O
M10	I/O
M12	GND
M14	GND
M16	V_{CCI}
M18	I/O
M20	I/O
M22	I/O
M24	I/O
N1	I/O
N3	V_{CCA}
N5	V_{CCR}
N7	I/O
N9	V_{CCI}
N11	GND
N13	GND
N15	GND
N17	I/O
N19	I/O
N21	I/O
N23	V_{CCR}
N25	V_{CCA}
P2	I/O
P4	I/O
P6	I/O
P8	I/O
P10	I/O
P12	GND
P14	GND
P16	I/O
P18	I/O
P20	NC
P22	I/O
P24	I/O
R1	I/O
R3	I/O

313-Pin PBGA	
Pin Number	**A54SX32 Function**
R5	I/O
R7	I/O
R9	I/O
R11	I/O
R13	GND
R15	I/O
R17	I/O
R19	I/O
R21	I/O
R23	I/O
R25	I/O
T2	I/O
T4	I/O
T6	I/O
T8	I/O
T10	I/O
T12	I/O
T14	HCLK
T16	I/O
T18	I/O
T20	I/O
T22	I/O
T24	I/O
U1	I/O
U3	I/O
U5	V_{CCI}
U7	I/O
U9	I/O
U11	I/O
U13	I/O
U15	I/O
U17	I/O
U19	I/O
U21	I/O
U23	I/O
U25	I/O
V2	V_{CCA}
V4	I/O
V6	I/O
V8	I/O

313-Pin PBGA	
Pin Number	**A54SX32 Function**
V10	I/O
V12	I/O
V14	I/O
V16	NC
V18	I/O
V20	I/O
V22	V_{CCA}
V24	V_{CCI}
W1	I/O
W3	I/O
W5	I/O
W7	NC
W9	I/O
W11	I/O
W13	V_{CCI}
W15	I/O
W17	I/O
W19	I/O
W21	I/O
W23	I/O
W25	I/O
Y2	I/O
Y4	I/O
Y6	I/O
Y8	I/O
Y10	I/O
Y12	I/O
Y14	I/O
Y16	I/O
Y18	I/O
Y20	NC
Y22	I/O
Y24	NC

329-Pin PBGA	
Pin Number	**A54SX32 Function**
D3	I/O
D4	TCK, I/O
D5	I/O
D6	I/O
D7	I/O
D8	I/O
D9	I/O
D10	I/O
D11	V_{CCA}
D12	V_{CCR}
D13	I/O
D14	I/O
D15	I/O
D16	I/O
D17	I/O
D18	I/O
D19	I/O
D20	I/O
D21	I/O
D22	I/O
D23	I/O
E1	V_{CCI}
E2	I/O
E3	I/O
E4	I/O
E20	I/O
E21	I/O
E22	I/O
E23	I/O
F1	I/O
F2	TMS
F3	I/O
F4	I/O
F20	I/O
F21	I/O

329-Pin PBGA	
Pin Number	**A54SX32 Function**
F22	I/O
F23	I/O
G1	I/O
G2	I/O
G3	I/O
G4	I/O
G20	I/O
G21	I/O
G22	I/O
G23	GND
H1	I/O
H2	I/O
H3	I/O
H4	I/O
H20	V_{CCA}
H21	I/O
H22	I/O
H23	I/O
J1	NC
J2	I/O
J3	I/O
J4	I/O
J20	I/O
J21	I/O
J22	I/O
J23	I/O
K1	I/O
K2	I/O
K3	I/O
K4	I/O
K10	GND
K11	GND
K12	GND
K13	GND
K14	GND

329-Pin PBGA	
Pin Number	**A54SX32 Function**
K20	I/O
K21	I/O
K22	I/O
K23	I/O
L1	I/O
L2	I/O
L3	I/O
L4	V_{CCR}
L10	GND
L11	GND
L12	GND
L13	GND
L14	GND
L20	V_{CCR}
L21	I/O
L22	I/O
L23	NC
M1	I/O
M2	I/O
M3	I/O
M4	V_{CCA}
M10	GND
M11	GND
M12	GND
M13	GND
M14	GND
M20	V_{CCA}
M21	I/O
M22	I/O
M23	V_{CCI}
N1	I/O
N2	I/O
N3	I/O
N4	I/O
N10	GND

329-Pin PBGA	
Pin Number	**A54SX32 Function**
N11	GND
N12	GND
N13	GND
N14	GND
N20	NC
N21	I/O
N22	I/O
N23	I/O
P1	I/O
P2	I/O
P3	I/O
P4	I/O
P10	GND
P11	GND
P12	GND
P13	GND
P14	GND
P20	I/O
P21	I/O
P22	I/O
P23	I/O
R1	I/O
R2	I/O
R3	I/O
R4	I/O
R20	I/O
R21	I/O
R22	I/O
R23	I/O
T1	I/O
T2	I/O
T3	I/O
T4	I/O
T20	I/O
T21	I/O

329-Pin PBGA	
Pin Number	**A54SX32 Function**
T22	I/O
T23	I/O
U1	I/O
U2	I/O
U3	V_{CCA}
U4	I/O
U20	I/O
U21	V_{CCA}
U22	I/O
U23	I/O
V1	V_{CCI}
V2	I/O
V3	I/O

329-Pin PBGA	
Pin Number	**A54SX32 Function**
V4	I/O
V20	I/O
V21	I/O
V22	I/O
V23	I/O
W1	I/O
W2	I/O
W3	I/O
W4	I/O
W20	I/O
W21	I/O
W22	I/O

329-Pin PBGA	
Pin Number	**A54SX32 Function**
W23	NC
Y1	NC
Y2	I/O
Y3	I/O
Y4	GND
Y5	I/O
Y6	I/O
Y7	I/O
Y8	I/O
Y9	I/O
Y10	I/O
Y11	I/O

329-Pin PBGA	
Pin Number	**A54SX32 Function**
Y12	V_{CCA}
Y13	V_{CCR}
Y14	I/O
Y15	I/O
Y16	I/O
Y17	I/O
Y18	I/O
Y19	I/O
Y20	GND
Y21	I/O
Y22	I/O
Y23	I/O

144-Pin FBGA	
Pin Number	**A54SX08 Function**
A1	I/O
A2	I/O
A3	I/O
A4	I/O
A5	V_{CCA}
A6	GND
A7	CLKA
A8	I/O
A9	I/O
A10	I/O
A11	I/O
A12	I/O
B1	I/O
B2	GND
B3	I/O
B4	I/O
B5	I/O
B6	I/O
B7	CLKB
B8	I/O
B9	I/O
B10	I/O
B11	GND
B12	I/O
C1	I/O
C2	I/O
C3	TCK, I/O
C4	I/O
C5	I/O
C6	PRA, I/O
C7	I/O
C8	I/O
C9	I/O
C10	I/O
C11	I/O
C12	I/O

144-Pin FBGA	
Pin Number	**A54SX08 Function**
D1	I/O
D2	V_{CCI}
D3	TDI, I/O
D4	I/O
D5	I/O
D6	I/O
D7	I/O
D8	I/O
D9	I/O
D10	I/O
D11	I/O
D12	I/O
E1	I/O
E2	I/O
E3	I/O
E4	I/O
E5	TMS
E6	V_{CCI}
E7	V_{CCI}
E8	V_{CCI}
E9	V_{CCA}
E10	I/O
E11	GND
E12	I/O
F1	I/O
F2	I/O
F3	V_{CCR}
F4	I/O
F5	GND
F6	GND
F7	GND
F8	V_{CCI}
F9	I/O
F10	GND
F11	I/O
F12	I/O

144-Pin FBGA	
Pin Number	**A54SX08 Function**
G1	I/O
G2	GND
G3	I/O
G4	I/O
G5	GND
G6	GND
G7	GND
G8	V_{CCI}
G9	I/O
G10	I/O
G11	I/O
G12	I/O
H1	I/O
H2	I/O
H3	I/O
H4	I/O
H5	V_{CCA}
H6	V_{CCA}
H7	V_{CCI}
H8	V_{CCI}
H9	V_{CCA}
H10	I/O
H11	I/O
H12	V_{CCR}
J1	I/O
J2	I/O
J3	I/O
J4	I/O
J5	I/O
J6	PRB, I/O
J7	I/O
J8	I/O
J9	I/O
J10	I/O
J11	I/O
J12	V_{CCA}

144-Pin FBGA	
Pin Number	**A54SX08 Function**
K1	I/O
K2	I/O
K3	I/O
K4	I/O
K5	I/O
K6	I/O
K7	GND
K8	I/O
K9	I/O
K10	GND
K11	I/O
K12	I/O
L1	GND
L2	I/O
L3	I/O
L4	I/O
L5	I/O
L6	I/O
L7	HCLK
L8	I/O
L9	I/O
L10	I/O
L11	I/O
L12	I/O
M1	I/O
M2	I/O
M3	I/O
M4	I/O
M5	I/O
M6	I/O
M7	V_{CCA}
M8	I/O
M9	I/O
M10	I/O
M11	TDO, I/O
M12	I/O

Datasheet Information

List of Changes

The following table lists critical changes that were made in the current version of the document.

Previous Version	Changes in Current Version (v3.2)	Page
v3.1 (June 2003)	The "Ordering Information" was updated to include RoHS information.	1-ii
	The Product Plan was removed since all products have been released.	N/A
	Information concerning the TRST pin in the "Probe Circuit Control Pins" section was removed.	1-6
	The "Dedicated Test Mode" section is new.	1-6
	The "Programming" section is new.	1-7
	A note was added to the "Power-Up Sequencing" table.	1-15
	A note was added to the "Power-Down Sequencing" table. The 3.3 V comments were updated for the following devices: A54SX08, A54SX16, A54SX32.	1-15
	U11 and U13 were added to the "313-Pin PBGA" table.	2-17
v3.0.1	Storage temperature in Table 1-3 was updated.	1-7
	Table 1-1 was updated.	1-5

Datasheet Categories

In order to provide the latest information to designers, some datasheets are published before data has been fully characterized. Datasheets are designated as "Product Brief," "Advanced," "Production," and "Datasheet Supplement." The definitions of these categories are as follows:

Product Brief

The product brief is a summarized version of a datasheet (advanced or production) containing general product information. This brief gives an overview of specific device and family information.

Advanced

This datasheet version contains initial estimated information based on simulation, other products, devices, or speed grades. This information can be used as estimates, but not for production.

Unmarked (production)

This datasheet version contains information that is considered to be final.

Datasheet Supplement

The datasheet supplement gives specific device information for a derivative family that differs from the general family datasheet. The supplement is to be used in conjunction with the datasheet to obtain more detailed information and for specifications that do not differ between the two families.

International Traffic in Arms Regulations (ITAR) and Export Administration Regulations (EAR)

The products described in this datasheet are subject to the International Traffic in Arms Regulations (ITAR) or the Export Administration Regulations (EAR). They may require an approved export license prior to their export. An export can include a release or disclosure to a foreign national inside or outside the United States.